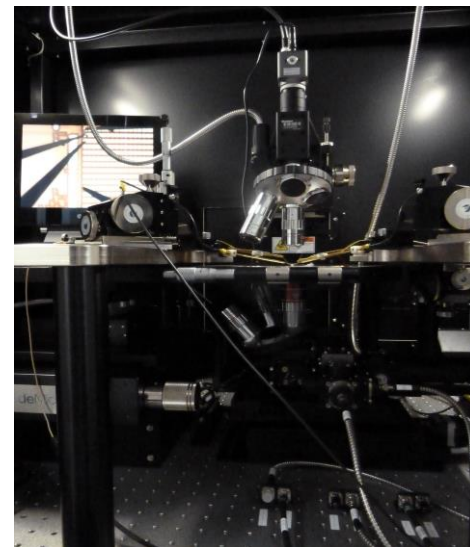


Objectifs du projet:

- Provide IC designers early evaluation tools for laser attacks
- Laser/Silicon interaction modeling
 - Physics , Electrical, Behavioral
- Deep submicron technologies sensitiveness evaluation
- Mixed-level simulation tool
- Emulation platform
- Countermeasures



■ TYPE DE PROJET: Basic Research
■ TYPE DE RECHERCHE:
■ COUT COMPLET : 2376163
■ AIDE DE L'ANR: 696475
■ DATE DE DEMARRAGE: 01/10/2012
■ DUREE: 42 mois
■ SITE WEB:

<http://www.anr-liesse.fr/index.php/fr/>

■ Coordinateur du projet: LIRMM
■ Partenaire 1: STMicroelectronics
■ Partenaire 2: Onera
■ Partenaire 3: TIMA
■ Partenaire 4: LCIS
■ Partenaire 5: ENSMSE

LIESSE Laser-Induced fault Effects in
Security-dedicated circuitS

